

Search Notes

Application/Control No.

10/616,492

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

LEE, YAO-SHENG

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	58	11/15/2005	BT
216	63	11/15/2005	BT
216	68	11/15/2005	BT
216	74	11/15/2005	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	11/15/2005	BT